

Date Searched: 7/11/2003

Databases Searched: USPAT, USPGPUB

Plurals: ON

Terms Searched:

L1 716/\$.ccls. or 703/1,2.ccls. or 382/141-152,154,190-206.ccls.

L2 symmetr\$6 near5 (area or window or partition\$3)

L3 (defect\$3 or fault or bad) same (deviat\$4 or tolerance or threshold or thresh-hold or range) same symmetr \$6

L4 1 and 2 and 3

Results: 1 hit

L5 2 and 3

Results: 16 hits

US 5345514 A	USPAT Mahdavi, Yaghou, et al.	382/152
US 4579455 A	USPAT Levy, Kenneth et al.	356/394
US 4559603 A	USPAT Yoshikawa, Ryoichi	716/5
US 3972616 A	USPAT Minami, Masana et al.	356/71
US 20030099022 A1	US-PGPUB Karin, Jacob et al.	359/201
US 6515913 B2	USPAT Kajigaya, Kazuhiko et al.	365/189.02
US 6498685 B1	USPAT Johnson, Kenneth C.	359/626

Databases Searched: EPO, JPO, IBM TDB, Derwent

Plurals: ON

Terms Searched:

L1 symmetr\$6 near5 (area or window or partition\$3)

L2 (defect\$3 or fault or bad) same (deviat\$4 or tolerance or threshold or thresh-hold or range) same symmetr \$6

L3 1 and 2

Results: 4 hits

JP 04311277 A JPO SHOJI, HIROYUKI

Database Searched: IEEE/IEEE Xplore

Terms Searched: (symmetr\* <near/5> (area or window or partition\*)) and (defect\* or fault or bad) and (deviat\* or tolerance or threshold or thresh-hold or range) and symmetr\*

Results: Your search matched 3 of 951805 documents.

Terms Searched: (area or window or partition\*) and (defect\* or fault or bad) and (deviat\* or tolerance or threshold or thresh-hold or range) and symmetr\*

Results: Your search matched 19 of 951805 documents.

Terms Searched: (defect\* or fault or bad) and symmetr\* and image

Results: Your search matched 14 of 951805 documents.